TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOS IV)

# **TPC8026**

Lithium Ion Battery Applications Portable Equipment Applications Notebook PC Applications

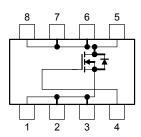
- Small footprint due to small and thin package
- Low drain-source ON resistance:  $RDS(ON) = 5.1 \text{ m}\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 30 \text{ S (typ.)}$
- Low leakage current:  $I_{DSS} = 10 \mu A \text{ (max) (V}_{DS} = 30 \text{ V)}$
- Enhancement mode:  $V_{th} = 1.3 \text{ to } 2.5 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA)}$

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characte	ristics	Symbol	Rating	Unit		
Drain-source voltage		$V_{DSS}$	30	V		
Drain-gate voltage (R	$k_{GS} = 20 \text{ k}\Omega$ )	$V_{DGR}$	-			
Gate-source voltage		$V_{GSS}$	±20	V		
Drain current	DC (Note 1)	ΙD	13	А		
Drain current	Pulse (Note 1)	I <sub>DP</sub>	52	A		
Drain power dissipati	on $(t = 10 s)$ (Note 2a)	$P_{D}$	1.9	W		
Drain power dissipati	on (t = 10 s) (Note 2b)	P <sub>D</sub>	1.0	W		
Single pulse avalance	ne energy (Note 3)	E <sub>AS</sub>	44	mJ		
Avalanche current		I <sub>AR</sub>	13	Α		
Repetitive avalanche	energy Note 2a) (Note 4)	E <sub>AR</sub>	0.048	mJ		
Channel temperature		T <sub>ch</sub>	150	°C		
Storage temperature	range	T <sub>stg</sub>	-55 to 150	°C		

Weight: 0.08 g (typ.)

### **Circuit Configuration**



Note 1, Note 2, Note 3 and Note 4: See the next page.

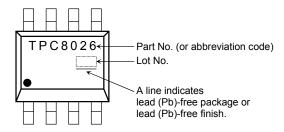
Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Please handle with caution.

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	R <sub>th (ch-a)</sub>	65.8	°C/W
Thermal resistance, channel to ambient (t = 10 s) (Note 2b)	R <sub>th (ch-a)</sub>	125	°C/W

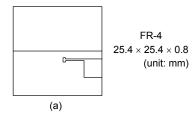
## Marking (Note 5)

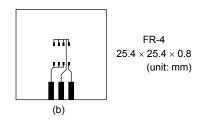


Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: (a) Device mounted on a glass-epoxy board (a)

(b) Device mounted on a glass-epoxy board (b)

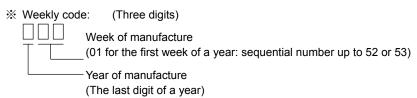




Note 3:  $V_{DD} = 24 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$  (initial), L = 0.2 mH,  $I_{AR} = 13 \text{ A}$ 

Note 4: Repetitive rating: pulse width limited by max channel temperature

Note 5: • on lower left of the marking indicates Pin 1.



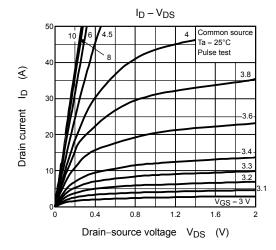


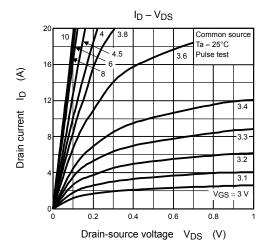
# **Electrical Characteristics (Ta = 25°C)**

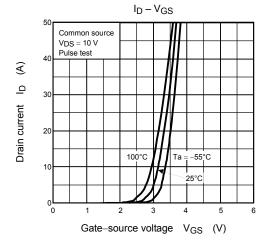
Cha	aracteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rrent	I <sub>GSS</sub>	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$		_	±100	nA
Drain cut-OFF cu	ırrent	I <sub>DSS</sub>	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V	_	_	10	μА
Drain-source breakdown voltage		V (BR) DSS	$I_D = 10$ mA, $V_{GS} = 0$ V	30	_	_	V
Dialii-source bre	akuowii voitage	V (BR) DSX	$I_D = 10$ mA, $V_{GS} = -20$ V	10	_	_	v
Gate threshold ve	oltage	V <sub>th</sub>	$V_{DS} = 10 \text{ V}, I_{D} = 1 \text{ mA}$	1.3	_	2.5	٧
Drain course ON	recistance	Pro (OV)	$V_{GS} = 4.5 \text{ V}, I_D = 6.5 \text{ A}$	±100 10 30 10	mΩ		
Dialii-source ON	resistance	R <sub>DS</sub> (ON)	$V_{GS} = 10 \text{ V}, I_D = 6.5 \text{ A}$		1117.5		
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 6.5 A	15	30	_	S
Input capacitance	e	C <sub>iss</sub>		_	1800	_	
Gate threshold voltage  Drain-source ON resistance  Forward transfer admittance  Input capacitance  Reverse transfer capacitance  Output capacitance  Rise time  Turn-ON time  Switching time  Fall time		C <sub>rss</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	370	_	pF
Output capacitan	ice	Coss		_	570	_	
· · ·	Rise time	t <sub>r</sub>	10 V 🗖	_	15	_	- ns
Cuitabina tima	Turn-ON time	t <sub>on</sub>	V <sub>GS</sub> 10 V I <sub>D</sub> = 6.5 A COUT	_	28	±100 — ±100 — 10 — — — — — — 2.5 7.5 10 5.1 6.6 30 — 800 — 870 — 670 — 670 — 670 — 228 — 21 — 642 — 6.5 — 665 —	
Switching time Fall	Fall time	t <sub>f</sub>	4.7 0	_	21	_	
	Turn-OFF time	t <sub>off</sub>	$V_{DD} \simeq 15 \text{ V}$ Duty $\leq$ 1%, $t_W = 10 \mu\text{s}$	_	54	_	
Total gate charge (gate-source plus		Qg		_	42	_	_
Gate-source charge 1		Q <sub>gs1</sub>	$V_{DD} \simeq 24 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 13 \text{ A}$	_	6.5	_	nC
Gate-drain ("mille	er") charge	Q <sub>gd</sub>	]	_	14	_	

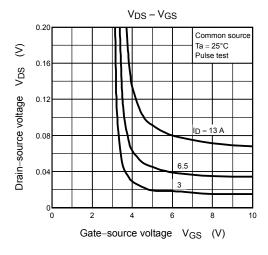
# Source-Drain Ratings and Characteristics (Ta = 25°C)

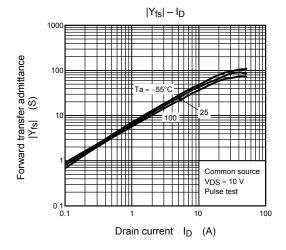
Characteris	stics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse	(Note 1)	I <sub>DRP</sub>	_	_	_	52	Α
Forward voltage (diode)			$V_{DSF}$	$I_{DR} = 13 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.2	V

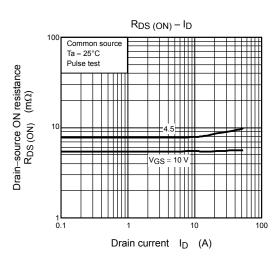




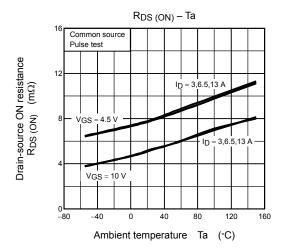


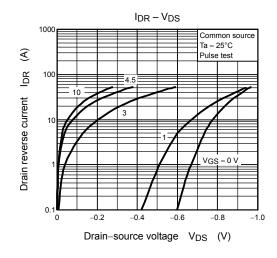


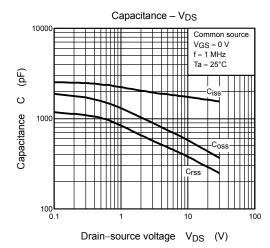


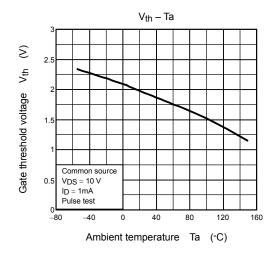


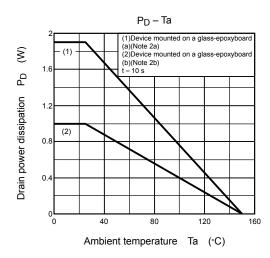
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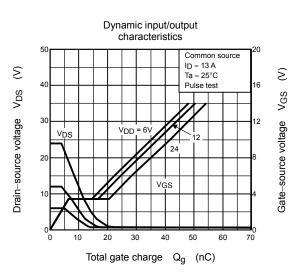




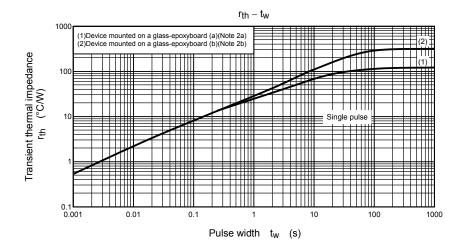


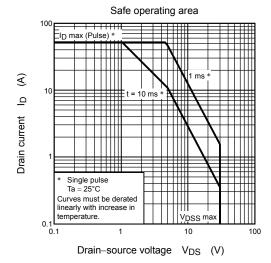






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